

Silicon VLSI Technology

Fundamentals, Practice and Modeling

James D. Plummer

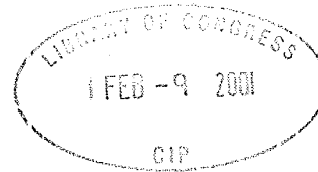
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Modern CMOS Technology

2

2.1 Introduction

In most of the remaining chapters in this book, we will discuss the process technologies used in silicon IC manufacturing individually. Individual technologies are clearly most useful when they are combined in a complete process flow sequence to produce chips. It is often the case that unit process steps are designed the way that they are because of the context in which those steps are used. For example, while a dopant may be diffused into a semiconductor to a desired final junction depth using many combinations of times and temperatures, the fact that the junction being formed might be diffused in the middle of a complex process flow may greatly restrict the possible choices of times and temperatures. In other words, the wafer's past history and the future process steps it may see can greatly influence how one chooses to perform a particular unit process step.

For this reason, and because we believe that understanding how complete process flows are put together aids understanding of individual process steps, we will describe in this chapter a complete modern Very Large Scale Integrated (VLSI) circuit process flow. The example we have chosen is typical of today's state of the art. CMOS technology has dominated silicon integrated circuits for the past 15 years and most people in the industry today believe that its dominance will continue for the foreseeable future for the reasons discussed in Chapter 1 (high performance, low power, supply voltage scalability, and circuit flexibility). In fact the SIA industry roadmap (NTRS) that we discussed in Chapter 1 assumes the continuation of CMOS technology through at least 2012.

For readers who are new to silicon technology, some of the ideas introduced in this chapter may not be fully appreciated until after later chapters on individual process steps have been read. However, we recommend that such people read this chapter before proceeding further because doing so will make the later material more understandable. A second reading of this chapter after the remainder of the book has been studied may also prove useful. In many cases, typical process conditions that might be used in a given step are presented in this chapter without full explanation. This is simply because we have not yet discussed the quantitative models and other tools at our disposal to calculate such parameters. As we do so in later chapters, we will revisit the CMOS process flow described here and discuss in more detail the reasons for particular process conditions used in this chapter.

2.2 CMOS Process Flow

Two typical CMOS circuits are shown in Figure 2-1. The simple inverter circuit on the left was described in Chapter 1. The NOR gate on the right illustrates how additional NMOS and PMOS devices can be added to the inverter circuit to realize more complex logic functions. In the NOR circuit, if either input 1 or input 2 or both of them are high, the output will be pulled to ground through one or both of the NMOS devices which will be turned on. Only if both inputs are low will the output be pulled high through the two series PMOS devices that are both turned on under this condition. The circuit thus implements the NOR function. To build these types of circuits, we need a technology that can integrate NMOS and PMOS devices on the same chip. In fact, many CMOS technologies also implement various types of resistors, capacitors, thin film transistors, and perhaps other types of devices as well. We will limit our discussion here to the two basic devices and describe a technology to build them. Extensions of this technology to include other components are reasonably straightforward and we will see some examples of such extensions in later chapters.

The end result of the process flow we will discuss is shown in Figure 2-2. To fabricate a structure like this, we will find that 16 photolithography steps and well over 100 individual process steps are required. The final integrated circuit may contain millions of components like those shown in the figure, each of which must work correctly.

There are two active device types shown in the figure, corresponding to those required to implement the circuits in Figure 2-1. The individual source, drain, and gate regions of the NMOS and PMOS devices are identifiable in the cross section. In addition to the active devices, there are many other parts to the overall structure. Some of the "overhead" is required to electrically isolate the active devices from each other. Other

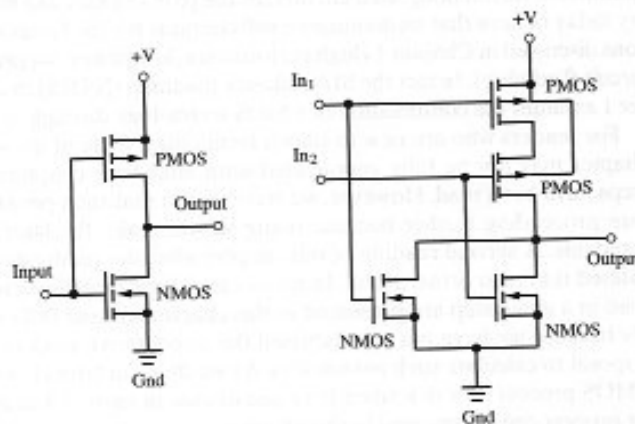


Figure 2-1 Simple CMOS circuits. An inverter is shown on the left and a NOR circuit on the right. The NOR circuit implements the function $\text{Output} = \overline{\text{In}_1 + \text{In}_2}$.

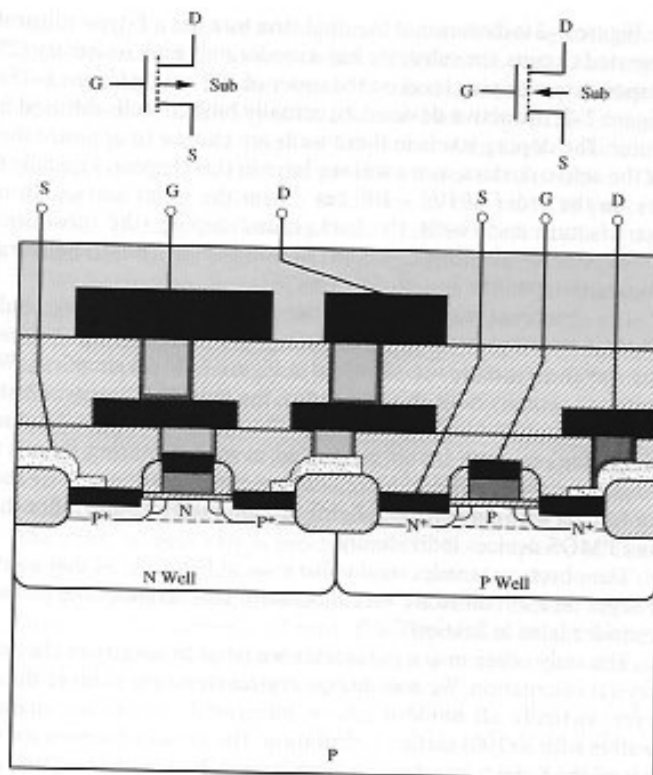


Figure 2-2 Cross section of the final CMOS integrated circuit. A PMOS transistor is shown on the left, an NMOS device on the right.

parts of the structure provide multiple wiring levels above the active devices to interconnect them to perform particular circuit functions. Finally, some regions are included simply to improve the performance of the individual devices by decreasing parasitic resistances or improving voltage ratings. As we proceed through the steps required to build this chip, we will discuss each of these points in greater detail.

2.2.1 The Beginning—Choosing a Substrate

Before we begin actual wafer fabrication, we must of course choose the starting wafers. In general this means specifying type (N or P), resistivity (doping level), crystal orientation, wafer size, and a number of other parameters having to do with wafer flatness, trace impurity levels, and so on. The major choices are the type, resistivity, and orientation.

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